

SSCS Switzerland supported the International Conference on Noise and Fluctuations (ICNF) 2019

The IEEE Solid-State Circuits Society (SSCS) Switzerland Chapter Supported organisation of the International Conference on Noise and Fluctuations (ICNF) 2019. The International Conference on Fluctuation Phenomena started in 1968 and moved all over the world. For the first time the conference is taking place in Switzerland, for its 25th edition (ICNF 2019) it was held in Neuchâtel (Switzerland), between June 18th to 21st.

The main organizing team was the Integrated Circuit Laboratory of the École Polytechnique Fédérale de Lausanne (EPFL) of Prof. Christian ENZ, chair of the Microengineering Institute.

The International Conference on Noise and Fluctuations (ICNF) is a biennial event that brings together researchers interested in theoretical and experimental aspects of fluctuations across a wide spectrum of scientific and technological fields. Since the development of the theory of Brownian motion, the science of fluctuation has been one of the most important parts of physics. The investigation of noise and fluctuation is indispensable for the understanding of the physical processes in various microscopic and macroscopic systems.

This conference is a great opportunity for noise researchers operating in very different areas of scientific and technological endeavour to come together and create the basis for continued and renewed cross-fertilization and collaboration.

The conference attracted 82 participants and 101 paper were accepted. The Figure 1 show a picture of the group attendee in front of the EPFL Neuchâtel Antenna also known as Microcity.



Figure 1 : Conference attendee group picture

Beside the regular session 4 plenary talks were organized on the following topic :

1. Ultra-Low-Noise Design of CMOS Image Sensors toward Photoelectron-Counting-Based Wide Dynamic Range Imaging.

By Shoji Kawahito, Shizuoka University

2. The Origin and the Measurement of Phase Noise in Oscillators.

By Enrico Rubiola, FEMTO-ST Institute

3. Nonstationary Low Frequency Noise in Switched MOSFET Circuits and Circuit Simulation.

By Alper Demir, Koç University

4. Low-Frequency Noise in Low -Dimensional van der Waals Materials.

By Alexander Balandin, University of California

The Figure 1 show a picture of the group attendee in front of



Figure 2 Audience at Alper Demir plenary talks.

The technical program was closed with 16 remarkable invited talks with a good mixture of academics and industry participants.

The social program brought the attendees to the old town castle, the history museum of Neuchâtel and a special tour at the International Watch Museum.

Taekwang Jang, Michel Bron, and Mathieu Coustans, For IEEE SSCS Switzerland Chapter.